

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

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Title of Invention

METHODS AND APPARATUS FOR DEFECT ISOLATION

Application Number :

Confirmation Number:

First Named Applicant: Leendert Huisman

Attorney Docket Number: BUR920030066US1

Art Unit:

Examiner:

Search string: (3761695 or 6308290 or 6490702 or 6516432).pn

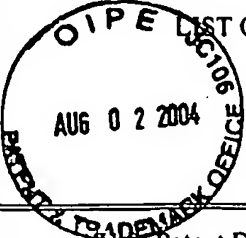
US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
2A	1	3761695	1973-09-25	Eichelberger			
2A	2	6308290	2001-10-23	Forlenza et al.			
3A	3	6490702	2002-12-03	Song et al.			
5A	4	6516432	2003-02-04	Motika et al.			

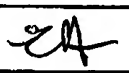


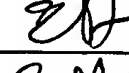

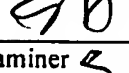
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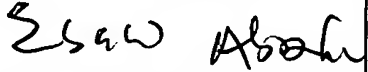

Examiner Name	Date
	11/08/06

U.S. Department of Commerce, Patent and Trademark Office <div style="display: flex; align-items: center;">  <div> LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary) </div> </div>					Docket No.: BUR920030066US1		Serial No.: 10/708,380	
					Applicant(s): Leendert M. Huisman et al.			
					Filing Date: February 27, 2004		Group: unknown	

U.S. Patent Documents							
*Examiner Initial	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

Foreign Patent Documents							Translation	
Document Number	Date	Country	Class	Subclass	Yes	No		
AG								
AH								
AI								

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
	AJ	E.B. Eichelberger, et al, "A Logic Design Structure for LSI Testability", Proceedings of the Fourteenth Design Automation Conference, New Orleans, 1977, pps. 462-468.
	AK	David P. Vallett, "IC Failure Analysis: The Importance of Test and Diagnostics", IEEE Design & Test of Computers, July-September 1997, pps. 76-82.
	AL	James L. Schafer et al. "Partner SRLS for Improved Shift Register Diagnostics", IEEE VLSI Test Symposium, June 1992, pps. 198-200.
	AM	Sandip Jundu, "Diagnosing Scan Chain Faults", IEEE Transactions On Very Large Scale Integration (VLSI) Systems, Vol. 2, No. 4, December 1994, pps. 512-517.
	AN	Samantha Edirisooriya et al., "Diagnosis of Scan Path Failures", Proceedings of IEEE VLSI Test Symposium April 1995, pps. 250-255.
	AO	Sridhar Narayanan et al., "An Efficient Scheme to Diagnose Scan Chains", International Test Conference, July 1997, pps. 704-713.

Examiner 	Date Considered 
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.